

GENERAL DESCRIPTION

The ME2302 is the N-Channel logic enhancement mode power field effect transistors, using high cell density, DMOS trench technology.

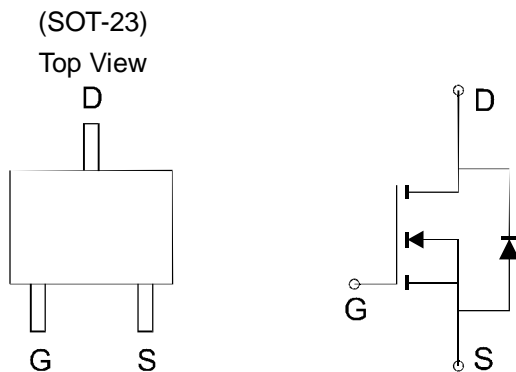
This high density process is especially tailored to minimize on-state resistance.

These devices are particularly suited for low voltage application such as cellular phone, notebook computer power management and other battery powered circuits, and low in-line power loss that are needed in a very small outline surface mount package.

ORDER INFORMATION

Device	Package
ME2302	SOT-23

PIN CONFIGURATION



FEATURES

- $R_{DS(ON)} \leq 85m\Omega @ V_{GS}=4.5V$
- $R_{DS(ON)} \leq 115m\Omega @ V_{GS}=2.5V$
- $R_{DS(ON)} \leq 135m\Omega @ V_{GS}=1.8V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Power Management in Notebook
- Portable Equipment
- Load Switch
- DSC

PIN DESCRIPTION

Pin	Symbol	Description
1	G	Gate
2	S	Source
3	D	Drain

Absolute Maximum Ratings ($T_A=25^\circ C$ Unless Otherwise Noted)

Parameter	Symbol	5 sec	Steady State	Unit
Drain-Source Voltage	V_{DSS}	20		V
Gate-Source Voltage	V_{GSS}	± 8		V
Continuous Drain Current ($t_J=150^\circ C$)	I_D	$T_A=25^\circ C$	2.8	A
		$T_A=70^\circ C$	2.2	
Pulsed Drain Current	I_{DM}	10		
Maximum Body-Diode Continuous Current	I_S	1.6		A
Maximum Power Dissipation	P_D	$T_A=25^\circ C$	1.25	W
		$T_A=70^\circ C$	0.8	
Operating Junction Temperature	T_J	150		$^\circ C$
Maximum Junction-to-Ambient	R_{thJA}	$T \leq 10$ sec	77	$^\circ C/W$
		Steady State	105	
Thermal Resistance-Junction to Case	$R_{\theta JC}$	70		$^\circ C/W$

*The device mounted on 1in² FR4 board with 2 oz copper

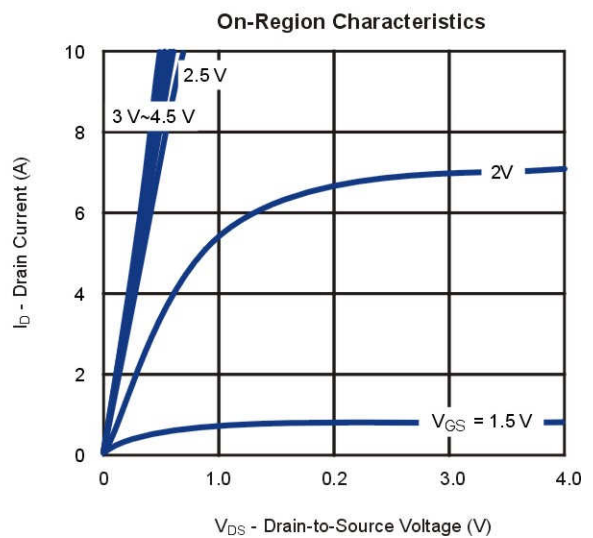
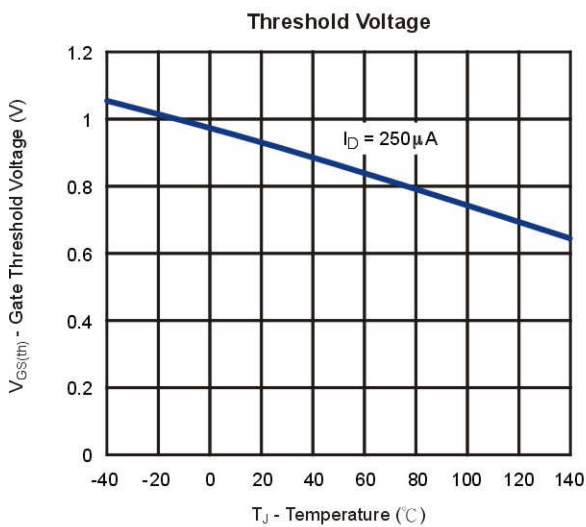
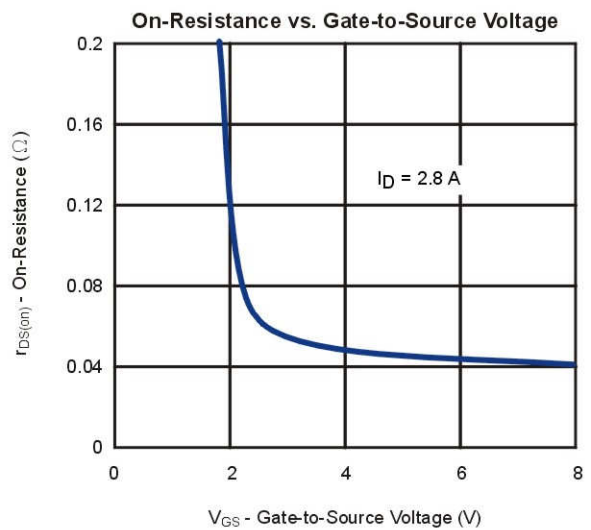
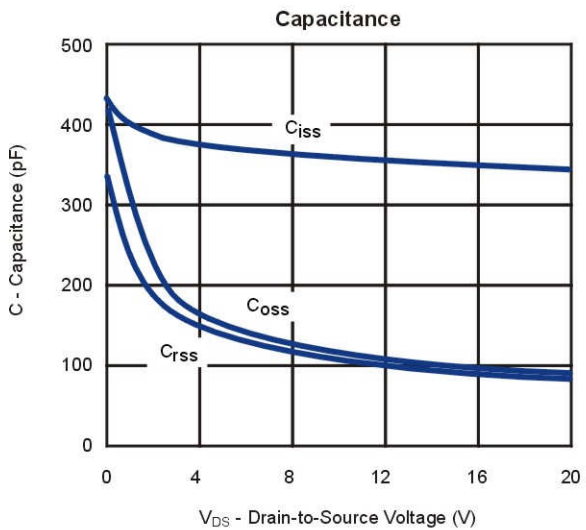
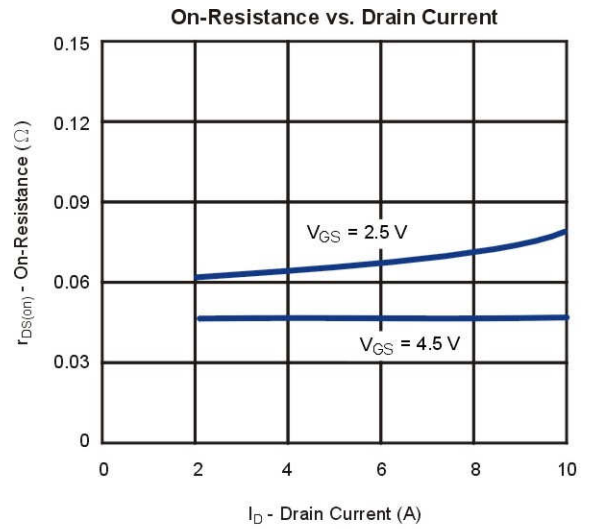
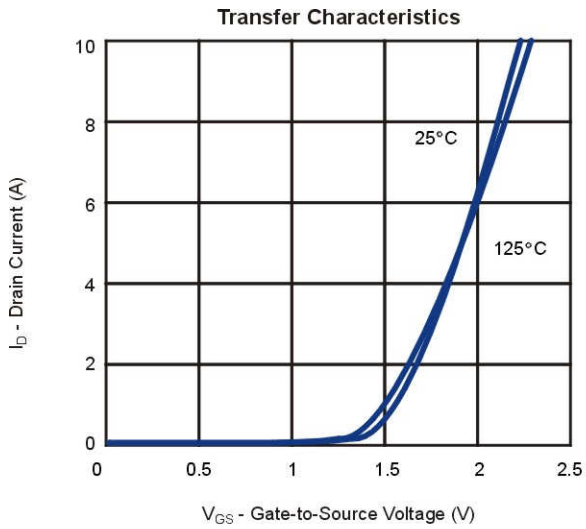
Electrical Characteristics (TA=25°C Unless Otherwise Specified)

Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC PARAMETERS						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250 μA	20			V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250 μA	0.6	0.9	1.2	
I _{GSS}	Gate-Body Leakage Current	V _{DS} =0V, V _{GS} =±8V			±100	nA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =20V, V _{GS} =0V			1	μA
		V _{DS} =20V, V _{GS} =0V			10	
		T _J =55°C				
I _{D(ON)}	On-State Drain Current ^a	V _{DS} ≥ 5V, V _{GS} = 4.5V	6			A
		V _{DS} ≥ 5V, V _{GS} = 2.5V	4			
R _{DS(ON)}	Drain-Source On-Resistance	V _{GS} =4.5V, I _D = 2.8A		55	85	mΩ
		V _{GS} =2.5V, I _D = 2.5A		65	115	
		V _{GS} =1.8V, I _D = 2.2A		80	130	
V _{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.75	1.2	V
DYNAMIC PARAMETERS						
Q _g	Total Gate Charge	V _{DS} =10V, V _{GS} =4.5V, I _D =2.8A		9		nC
Q _{gs}	Gate-Source Charge			2.2		
Q _{gd}	Gate-Drain Charge			3		
C _{iss}	Input Capacitance	V _{DS} =10V, V _{GS} =0V, f=1MHz		350		pF
C _{oss}	Output Capacitance			90		
C _{rss}	Reverse Transfer Capacitance			20		
t _{d(on)}	Turn-On Delay Time	V _{DD} =10V, R _L =10Ω V _{GEN} =4.5Ω, R _G =6Ω		9		ns
t _r	Rise Time			23		
t _{d(off)}	Turn-Off Delay Time			38		
t _f	Fall Time			3		

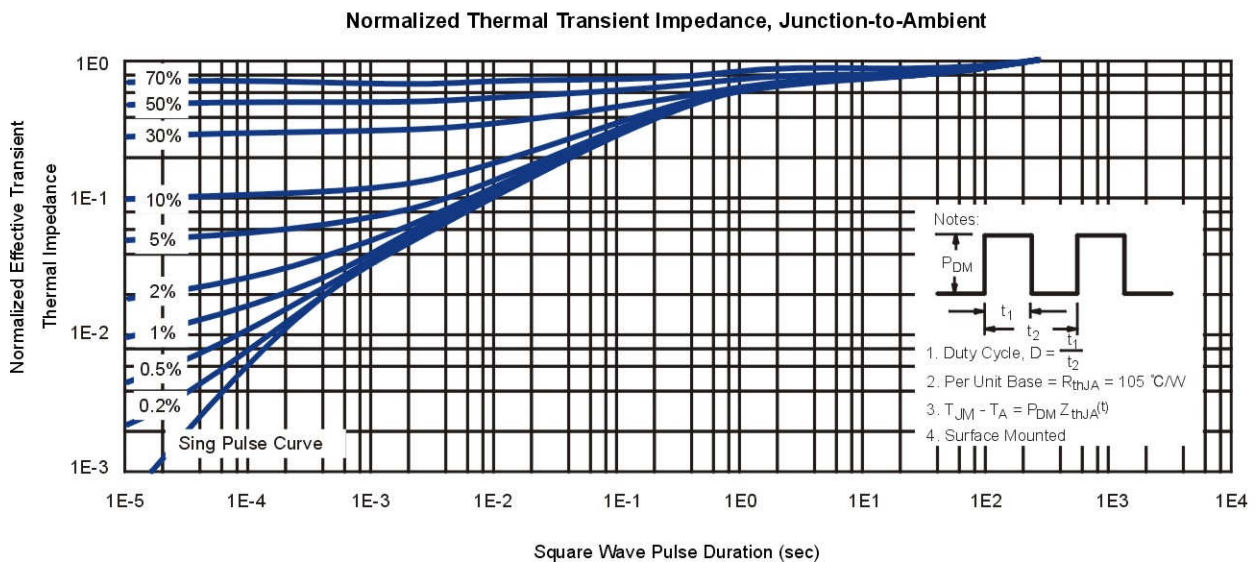
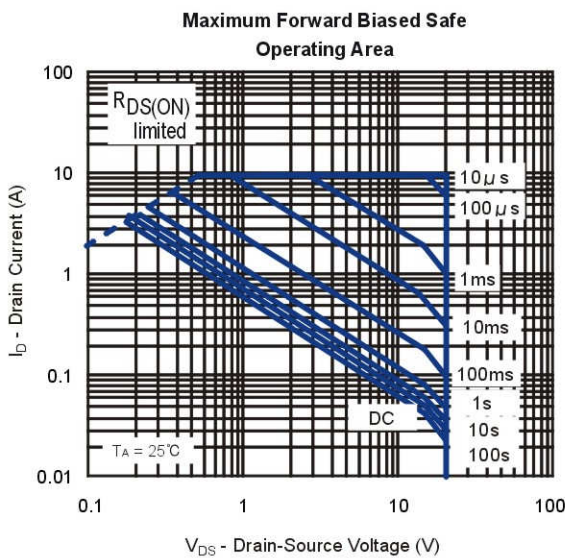
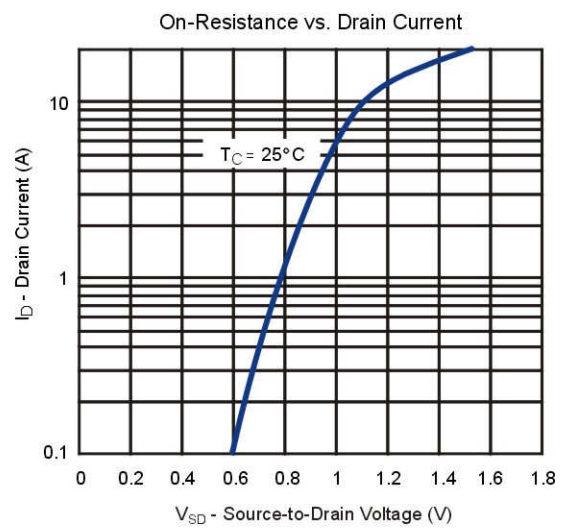
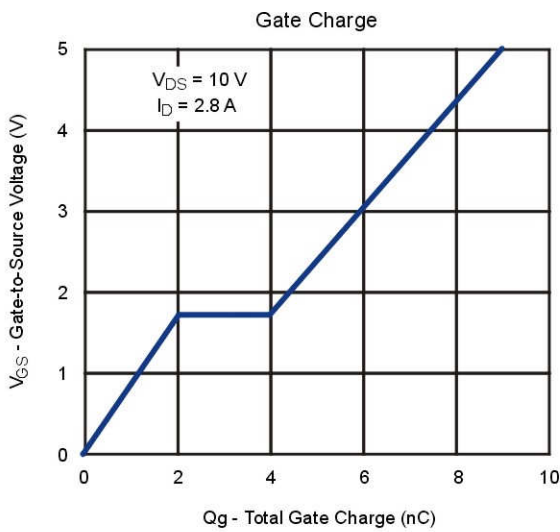
Notes:

a. Pulse test; pulse width ≤ 300us, duty cycle ≤ 2%

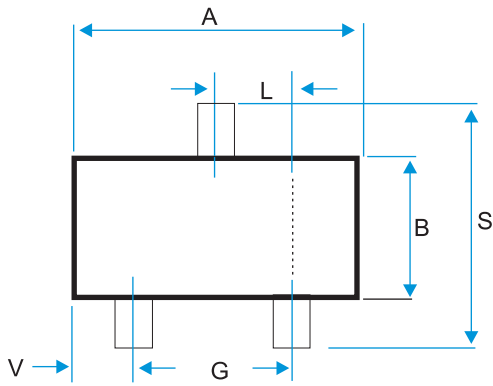
Typical Characteristics (T_J = 25°C Noted)



Typical Characteristics (T_J = 25°C Noted)



SOT-23 Package Outline



DIM	MILLIMETERS	
	MIN	MAX
A	2.80	3.1
B	1.20	1.7
C	0.89	1.3
D	0.37	0.50
G	1.78	2.04
H	0.013	0.15
J	0.085	0.2
K	0.45	0.7
L	0.89	1.02
S	2.10	3
V	0.45	0.60

